Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/564,482	BANNO ET AL.	
Examiner	Art Unit	
John P. Sheehan	1742	

	SEARCHED			
Class	Subclass	Date	Examiner	
	14			

	INTERFERENCE SEARCHED			
Subclass	Date	Examiner		
Search	9/26/2007	JPS		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	9/26/2007	JPS
PALM Inventor Name Search		